	Туре	Н #	Hits	Search Text	DBs	Time Stamp	Comments	Errors
Н	BRS	L1	60759	(gate and source and drain)	USPAT	2000/08/24 09:24		0
2	BRS	L2	0	l and (multi-insulating adj   layer)	USPAT	2000/08/24 09:25		0
ω	BRS	L3	10564	1 and (insulating adj layers)	USPAT	2000/08/24 09:27		0
4	BRS	L4	2	3 and HSQ	USPAT	2000/08/24 09:30		0
5	BRS	L5	200519	semiconductor	USPAT	2000/08/24 09:34		0
0	BRS	L6	24669	5 and insulating adj layers	USPAT	2000/08/24 09:36		0
7	BRS	L7	424050	6 and conductive ajd film	USPAT	2000/08/24 09:39		0
- ∞	BRS	L8	1428	6 AND CONDUCTIVE adj FILM	USPAT	2000/08/24 09:40		0
9	BRS	L9	0	8 and HSQ	USPAT	2000/08/24 09:40		0
10	BRS	L11	19	6 and 10	USPAT	2000/08/24 10:03		0
11	BRS	L12	3599	SiH	USPAT	00		0
12	BRS	L13	Н	10 and 12	USPAT	:00		0
13	BRS	L10	88	MSQ.	USPAT	2000/08/24 10:09		0
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5,660,849-50H- Dell "	65,849-	X. ±	6960	> #SR	) + c[ahb's	
					10107BL	•
438/474 ; 438/934 ; 438/953	438/143 ;	growing a resistive layer on a short lifetime	Methc epita	19860401 20	□ ⊠ US 4579601 <sub>3</sub>	9
257/770		method of manufacturing the	me same			
257/197	257/587 ;	nd method of manufacturing and semiconductor device	Device a the same and	19960730 30	□ ⊠ US 5541444 .	ω
		device	de			
438/257 ; 438/476 ; 438/586	438/43 ;	for manufacturing contact or a nonvolatile nductor	Method hole fo	19971021 8	□ ⊠ NS 5679590	7,7
138/253 438/396	438/240 4	device with	16 memory de capacitor	19980317   1		σ
438/398	438/235 4		Method			, ]
38/95	00 /057	of manufactur:	0	19990112 2	□ ⊠ US 5858837 A	О
38/636 438/74	438/624 ;	Method of manufacturing semiconductor device	16 Method semico	19990302 1	58	4
257/315 257/355 257/758 257/763	257/356 ;	Semiconductor device and method of manufacturing the same	11 Semico	19991102		ω
257/296	257/301 2	semiconductor integrated circuit and a method of manufacturing the same	14 and a same	19991207,]	□ ⊠ NS 5998822	2
438/675	438/258	nsistor	11 gate t	- 8T/0007	A	,
XRef	1	of manifacturing float:	Method		□ N US 6090667	
Current	Current OR	Title	Pag es	Issue Date	U 1 Document ID	
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